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Note : Mitsubishi Electric will continue the business operations of high frequency & optical devices and power devices.

Renesas Technology Corp.
Customer Support Dept.
April 1, 2003

M5M5V408BFP,TP,KV

4194304-BIT (524288-WORD BY 8-BIT) CMOS STATIC RAM

DESCRIPTION

The M5M5V408B is a family of low voltage 4-Mbit static RAMs organized as 524,288-words by 8-bit, fabricated by Mitsubishi's high-performance 0.25µm CMOS technology.

The M5M5V408B is suitable for memory applications where a simple interfacing, battery operating and battery

- Package:
 M5M5V408BFP: 32 pin 525 mil SOP
 M5M5V408BTP: 32 pin 400mil TSOP(II)
 M5M5V408BKV: 32 pin 8mm x13.4mm STSOP

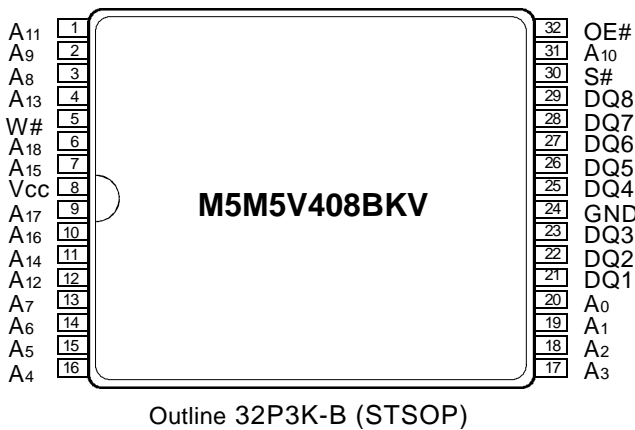
FEATURES

- Single 2.7 ~ 3.6V power supply
- Small stand-by current: 0.3µA (3V,typ.)
- No clocks, No refresh
- Data retention supply voltage=2.0V to 3.6V
- All inputs and outputs are TTL compatible.
- Easy memory expansion by S#
- Common Data I/O
- Three-state outputs: OR-tie capability
- OE# prevents data contention in the I/O bus
- Process technology: 0.25µm CMOS

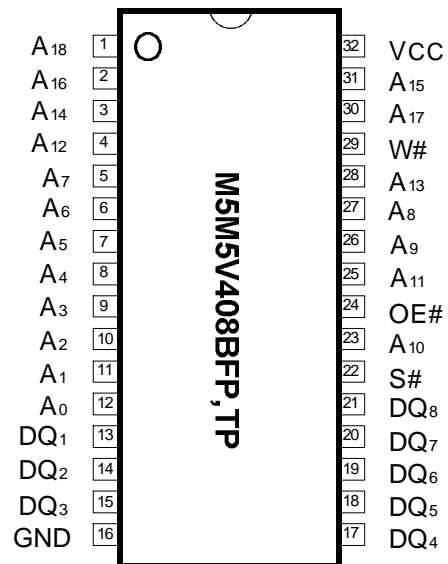
Version, Operating temperature	Part name (## stands for "FP", "TP" or "KV")	Power supply	Access time (max.)	Stand-by current I _{cc} (PD), V _{cc} =3.0V						Active current I _{cc} 1 (3.0V, typ.*)
				Typical *		Limits (max.)				
				25°C	40°C	25°C	40°C	70°C	85°C	
Standard 0 ~ 70°C	M5M5V408B## -70H	2.7 ~ 3.6V	70ns	0.3µA	1µA	1µA	3µA	15µA	-	30mA (10MHz)
	M5M5V408B## -85H		85ns							
I-version -40 ~ +85°C	M5M5V408B## -70HI	2.7 ~ 3.6V	70ns	0.3µA	1µA	1µA	3µA	15µA	30µA	5mA (1MHz)
	M5M5V408B## -85HI		85ns							

*Typical values are sampled, and are not 100% tested.

PIN CONFIGURATION (TOP VIEW)



Pin	Function
A0 ~ A18	Address input
DQ1 ~ DQ8	Data input / output
S# (\bar{S})	Chip select input
W# (\bar{W})	Write control input
OE# (\bar{OE})	Output enable input
Vcc	Power supply
GND	Ground supply



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FUNCTION

The M5M5408BFP,TP,KV is organized as 524,288-words by 8-bit. These devices operate on a single +2.7~3.6V power supply, and are directly TTL compatible to both input and output. Its fully static circuit needs no clocks and no refresh, and makes it useful.

A write operation is executed during the S# low and W# low overlap time. The address(A0~A18) must be set up before the write cycle

A read operation is executed by setting W# at a high level and OE# at a low level while S# are in an active

When setting S# at a high level, the chips are in a non-selectable mode in which both reading and writing are disabled. In this mode, the output stage is in a high-impedance state, allowing OR-tie with other chips. Setting the OE# at a high level, the output stage is in a high-impedance state, and the data bus contention problem in the write cycle is eliminated.

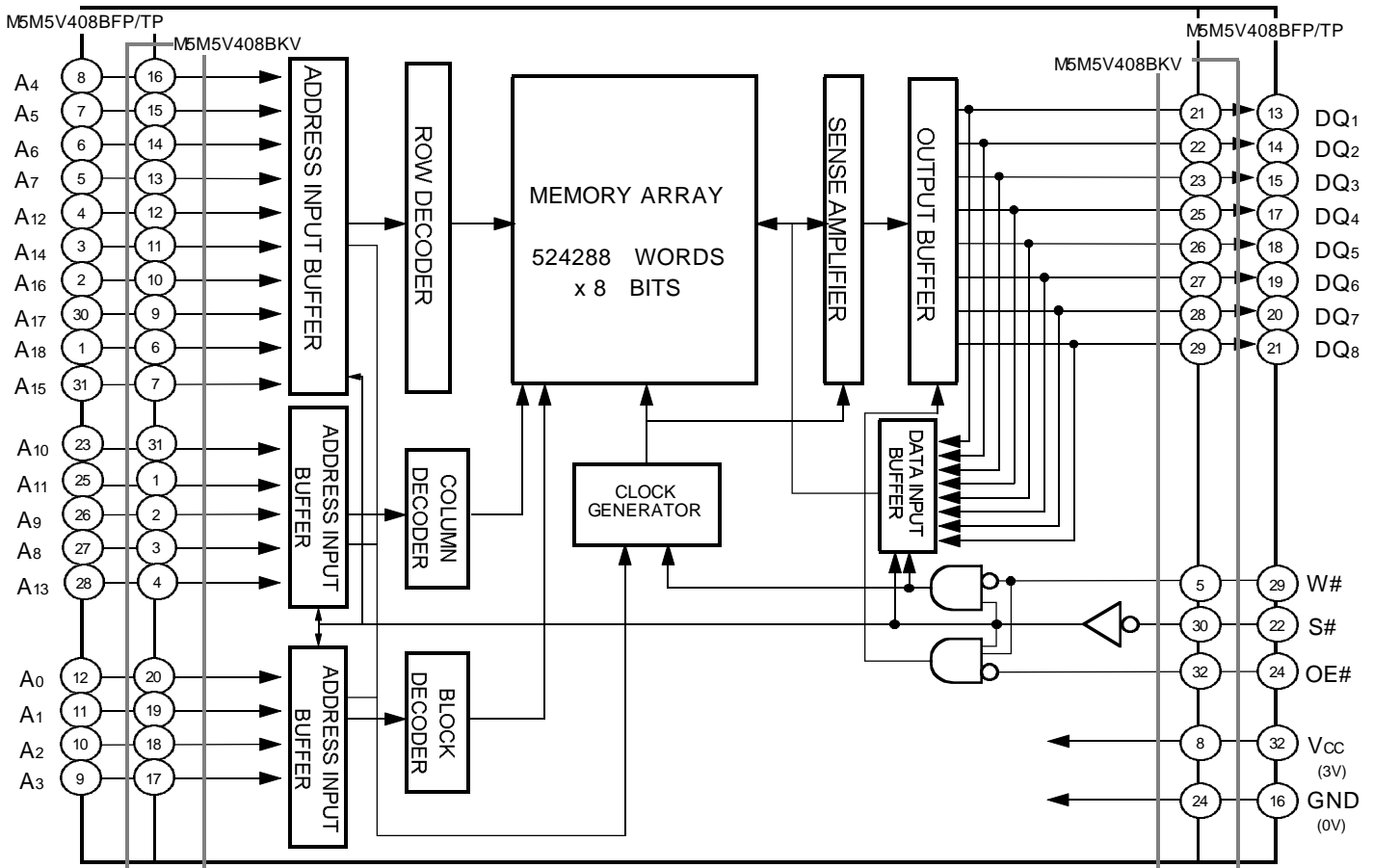
The power supply current is reduced as low as 0.3μA(25°C, typical), and the memory data can be held at +2V power supply, enabling battery back-up operation during power failure or power-down operation in the non-

FUNCTION TABLE

S#	W#	OE#	Mode	DQ	Icc
H	X	X	Non selection	High-impedance	Standby
L	L	X	Write	Data input (D)	Active
L	H	L	Read	Data output (Q)	Active
L	H	H	Read	High-impedance	Active

note: "H" and "L" in this table mean VIH and VIL, respectively. "X" in this table should be "H" or "L".

BLOCK DIAGRAM



M5M5V408BFP,TP,KV**4194304-BIT (524288-WORD BY 8-BIT) CMOS STATIC RAM****ABSOLUTE MAXIMUM RATINGS**

Symbol	Parameter	Conditions	Ratings	Units
V _{CC}	Supply voltage	With respect to GND	-0.5* ~ +4.6	V
V _I	Input voltage	With respect to GND	-0.5* ~ V _{CC} + 0.5	
V _O	Output voltage	With respect to GND	0 ~ V _{CC}	
P _d	Power dissipation	T _a =25°C	700	mW
T _a	Operating temperature	Standard (Commercial temp.)	0 ~ 70	°C
		I-version (Industrial temp.)	- 40 ~ +85	
T _{stg}	Storage temperature		- 65 ~ +150	°C

* -3.0V in case of AC (Pulse width ≤ 30ns)

DC ELECTRICAL CHARACTERISTICS(V_{CC}=2.7 ~ 3.6V, unless otherwise noted)

Symbol	Parameter	Conditions	Limits			Units		
			Min	Typ	Max			
V _{IH}	High-level input voltage		2.2		V _{CC} +0.3V	V		
V _{IL}	Low-level input voltage		-0.3*		0.6			
V _{OH1}	High-level output voltage 1	I _{OH} = -0.5mA	2.4					
V _{OH2}	High-level output voltage 2	I _{OH} = -0.05mA	V _{CC} -0.5V					
V _{OL}	Low-level output voltage	I _{OL} =2mA			0.4			
I _I	Input leakage current	V _I =0 ~ V _{CC}			±1	μA		
I _O	Output leakage current	S#=V _{IH} or OE#=V _{IH} , V _{I/O} =0 ~ V _{CC}			±1	μA		
I _{CC1}	Active supply current (AC, CMOS-level)	S# ≤ 0.2V Output-open Other inputs ≤ 0.2V or ≥ V _{CC} -0.2V	f = 10MHz	-	30	45	mA	
			f = 1MHz	-	5	7		
I _{CC2}	Active supply current (AC, TTL-level)	S#=V _{IL} Output-open Other inputs=V _{IH} or V _{IL}	f = 10MHz	-	30	45	mA	
			f = 1MHz	-	5	7		
I _{CC3}	Stand by supply current (CMOS-level input)	V _{CC} =3.6V, max. S# ≥ V _{CC} -0.2V Other inputs=0~V _{CC}	I-version	85°C	-	-	40	μA
			I-version, standard	70°C	-	-	20	
				40°C	-	1	5	
			0 ~ +25°C	-	0.3	2		
I _{CC4}	Stand by supply current (TTL-level input)	S#=V _{IH} , Other inputs= 0 ~ V _{CC}	I-version	-40 ~ +25°C	-	0.3	2	mA
					-	-	0.5	

* -3.0V in case of AC (Pulse width ≤ 30ns)

Note 1: Direction for current flowing into IC is indicated as positive (no mark).

Note 2: Typical values are sampled at V_{CC}=3.0V, and are not 100% tested.**CAPACITANCE**(V_{CC}=2.7 ~ 3.6V, unless otherwise noted)

Symbol	Parameter	Conditions	Limits			Units
			Min	Typ	Max	
C _I	Input capacitance	V _I =GND, V _I =25mV _{rms} , f=1MHz			8	pF
C _O	Output capacitance	V _O =GND, V _O =25mV _{rms} , f=1MHz			10	

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AC ELECTRICAL CHARACTERISTICS (V_{CC}=2.7 ~ 3.6V, unless otherwise noted)

(1) TEST CONDITIONS

Supply voltage	2.7V~3.6V
Input pulse	V _{IH} =2.4V, V _{IL} =0.4V
Input rise time and fall time	5ns
Reference level	V _{OH} =V _{OL} =1.5V Transition is measured ±500mV from steady state voltage.(for t _{en} ,t _{dis})
Output loads	Fig.1,CL=30pF CL=5pF (for t _{en} ,t _{dis})

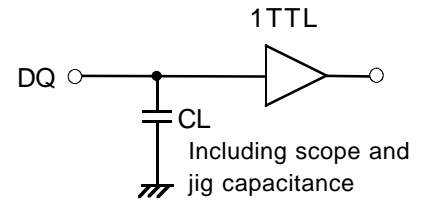


Fig.1 Output load

(2) READ CYCLE

Symbol	Parameter	Limits				Units
		-70H, -70HI		-85H, -85HI		
		Min	Max	Min	Max	
t _{CR}	Read cycle time	70				ns
t _{a(A)}	Address access time		70		85	ns
t _{a(S)}	Chip select access time		70		85	ns
t _{a(OE)}	Output enable access time		35		45	ns
t _{dis(S)}	Output disable time after S# high	25			25	ns
t _{dis(OE)}	Output disable time after OE# high	25			25	ns
t _{en(S)}	Output enable time after S# low	10		10		ns
t _{en(OE)}	Output enable time after OE# low	5		5		ns
t _{v(A)}	Data valid time after address	10		10		ns

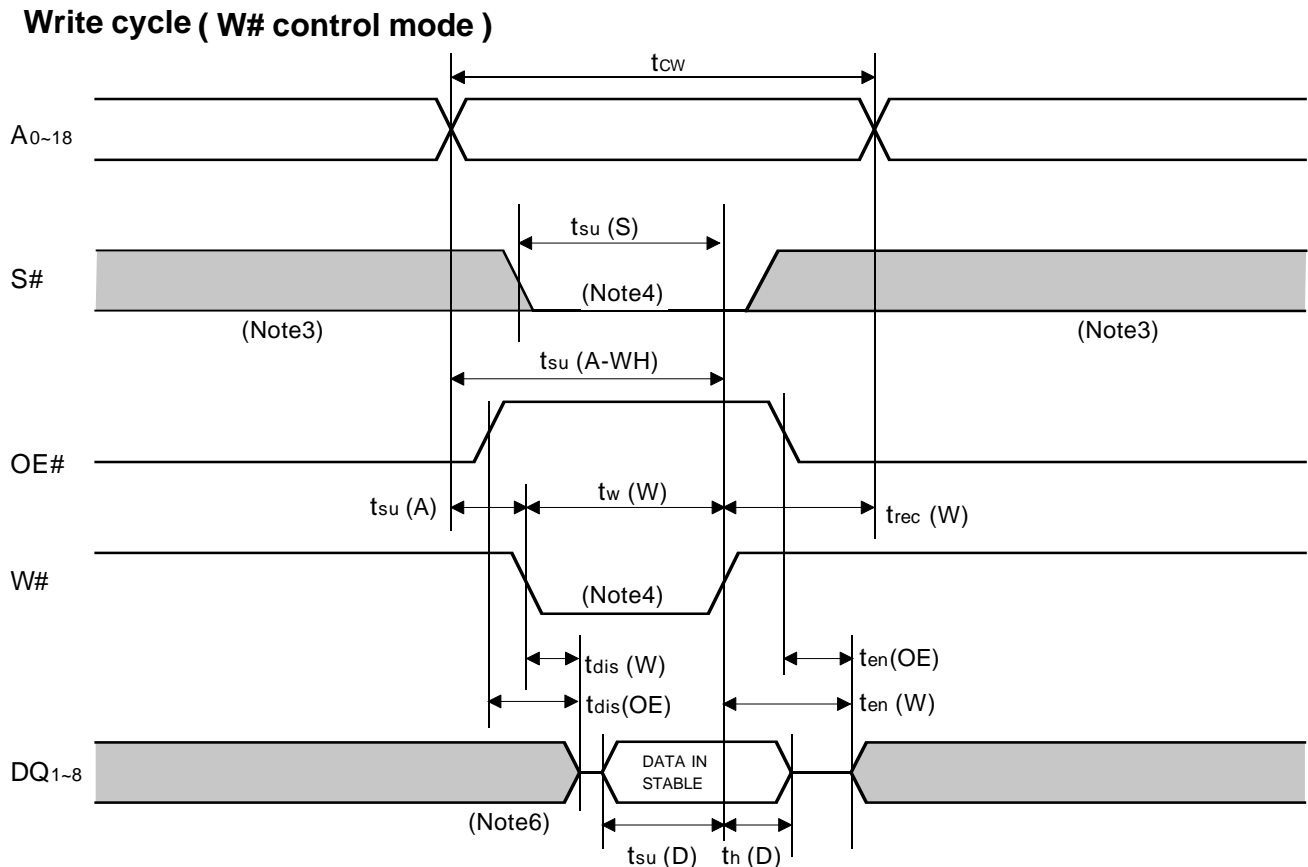
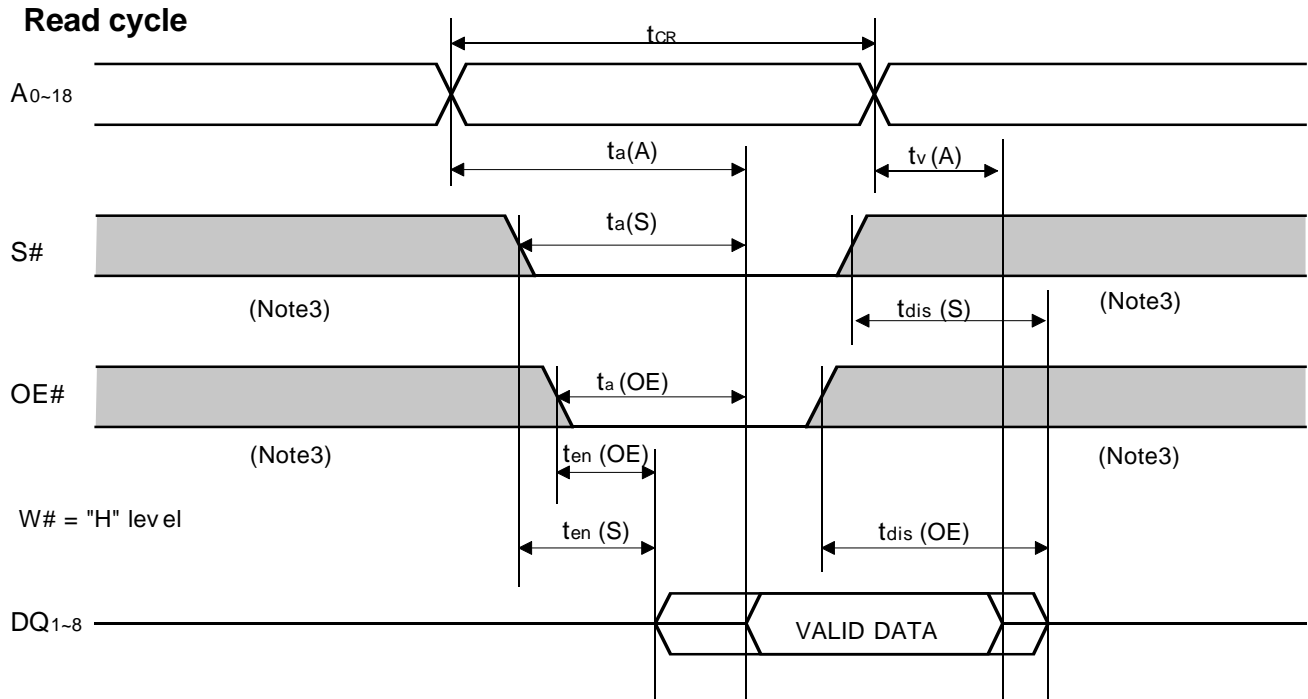
(3) WRITE CYCLE

Symbol	Parameter	Limits				Units
		-70H, -70HI		-85H, -85HI		
		Min	Max	Min	Max	
t _{cw}	Write cycle time	70		85		ns
t _{w(W)}	Write pulse width	55		55		ns
t _{su(A)}	Address set up time	0		0		ns
t _{su(A-WH)}	Address set up time with respect to W# high	65		65		ns
t _{su(S)}	Chip select set up time	65		65		ns
t _{su(D)}	Data set up time	35		35		ns
t _{h(D)}	Data hold time	0		0		ns
t _{rec(W)}	Write recovery time	0		0		ns
t _{dis(W)}	Output disable time after W# low		25		25	ns
t _{dis(OE)}	Output disable time after OE# high		25		25	ns
t _{en(W)}	Output enable time after W# high	5		5		ns
t _{en(OE)}	Output enable time after OE# low	5		5		ns

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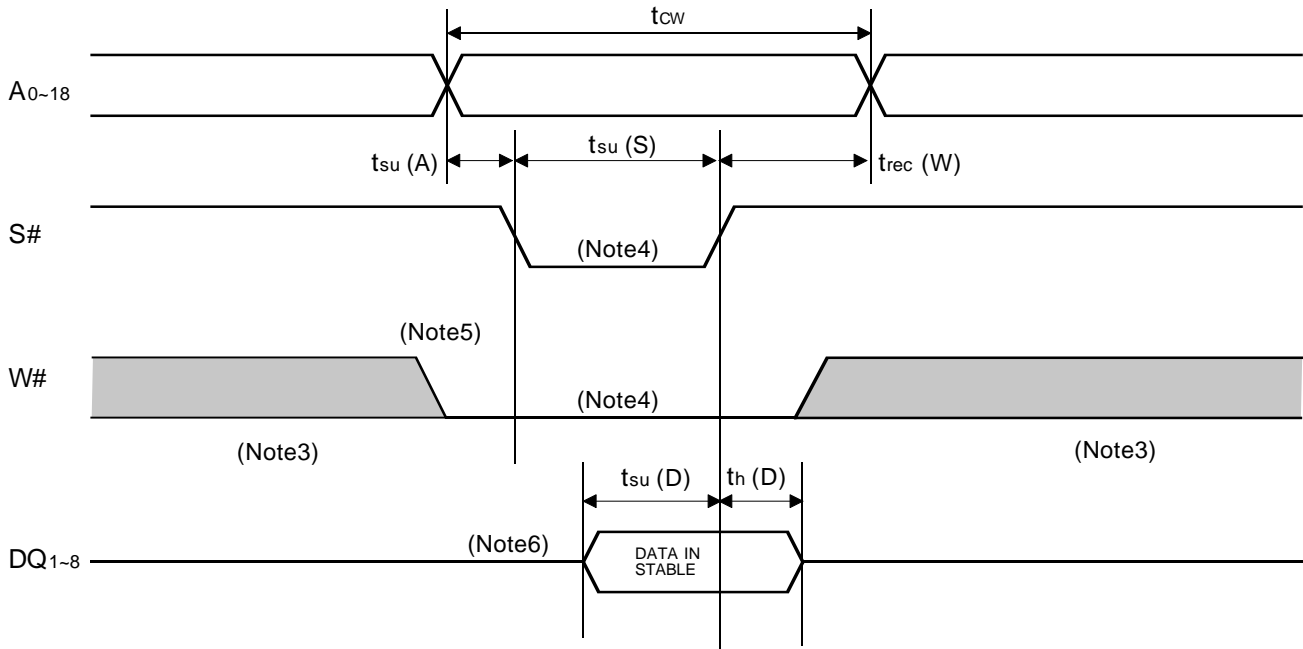
(4) TIMING DIAGRAMS



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Write cycle (S# control mode)



Note 3: Hatching indicates the state is "don't care".

Note 4: A Write occurs during the overlap of a low S# and a low W#.

Note 5: If W# goes low simultaneously with or prior to S#, the output remains in the high impedance state.

Note 6: Don't apply inverted phase signal externally when DQ pin is in output mode.

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POWER DOWN CHARACTERISTICS

(1) ELECTRICAL CHARACTERISTICS

Symbol	Parameter	Test conditions	Limits			Units		
			Min	Typ.	Max			
V _{CC} (PD)	Power down supply voltage		2.0			V		
V _I (S)	Chip select input S#		2.0			V		
I _{CC} (PD)	Power down supply current	V _{CC} =3.0V, S# ≥ V _{CC} -0.2V, Other inputs = 0 ~ V _{CC}	I-version	85°C	-	-	30	μA
			Standard,	70°C	-	-	15	
			I-version	40°C	-	1*	3	
			Standard	0~ 25°C	-	0.4*	1	
			I-version	-40~ 25°C	-	0.4*	1	

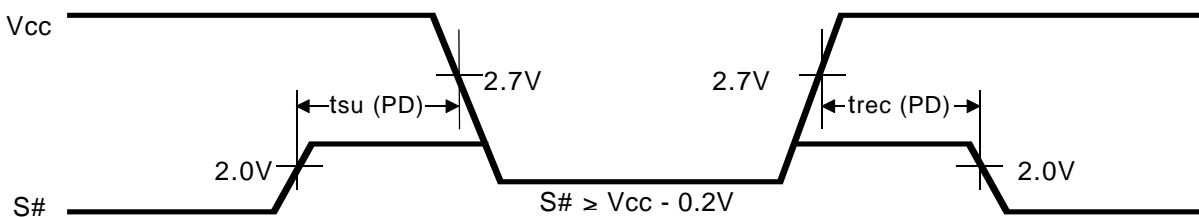
*Typical values are sampled, and are not 100% tested.

(2) TIMING REQUIREMENTS

Symbol	Parameter	Test conditions	Limits			Units
			Min	Typ	Max	
t _{su} (PD)	Power down set up time		0			ns
t _{rec} (PD)	Power down recovery time		5			ms

(3) TIMING DIAGRAM

S# control mode



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Revision History

<u>Revision No.</u>	<u>History</u>	<u>Date</u>	<u>Remarks</u>
K0.1e	The first edition	Mar. 5, 1998	Preliminary
K0.2e	Added M5M5V408BFP/TP/RT	Jul.30, 1998	Preliminary
K1.0e	The first product version	Sep.7, 1998	---
K2.0e	1) Speed items revised: 70ns added and 100ns deleted 2) lcc3 and lcc(PD) limits revised	Mar.10,1999	---
3.0e	1) Product lineup revised 2) Symbol notations revised: \overline{S} -> S#, \overline{W} -> W#, \overline{OE} -> OE#	Feb.12, 2002	---

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